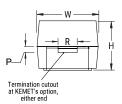


## T493A224K035BC6110

T493 HRA, Tantalum, MnO2 Tantalum, HRA, 0.22 uF, 10%, 35 VDC, SMD, MnO2, Molded, High Reliability, B (0.1%/1000 Hrs), 18 Ohms, 3216, 1.8 mm, 0.8 mm

CATHODE (-) END VIEW



ANODE (+) END VIEW

BOTTOM VIEW

SIDE VIEW

ΗB



General Information	
Series	T493 HRA
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, High Reliability
Features	High Reliability
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	652b281f-d242-4453-bc44-06 55d646cec3
Termination	Hot Solder Dipped
AEC-Q200	No
Typical Component Weight	58.97 mg
Notes	P and R dimensions represents the minimum solderable area of the termination surface entirely below cutout (if one is present).

Dimensions	
L	3.2mm +/-0.2mm
W	1.6mm +/-0.2mm
н	1.6mm +/-0.2mm
т	0.13mm REF
S	0.8mm +/-0.3mm
F	1.2mm +/-0.1mm
A	1.2mm MIN
В	0.4mm +/-0.15mm
E	1.3mm REF
G	1.1mm REF
Р	0.35mm MIN
R	0.4mm REF
Х	0.1mm +/-0.1mm REF

Specifications	
Capacitance	0.22 uF
Tolerance	10%
Voltage DC	35 VDC (85C), 23.45 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	4% 120Hz 25C
Failure Rate	B (0.1%/1000 Hrs)
ESR	18 Ohms (100kHz 25C)
Ripple Current	65 mA (rms, 100kHz 25C)
Leakage Current	0.5 uA (5min 25°C)
Testing and Reliability	Standard Testing Only

## **Packaging Specifications**

Packaging	T&R, 178mm
Packaging Quantity	2000

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